

ABSTRACT OF THE DISCLOSURE

The present invention discloses a method for testing a non-volatile memory, characterized in that the code assigned by the client is written in at least one non-volatile memory in advance, and then a particular pin of the non-volatile memory is cut, such as a write enabling pin for avoiding the mistake of rewriting. After restarting a testing machine, the code written in the non-volatile memory is read out to compare it with the code retrieved from a controlling program of the testing machine. If the comparing result is identical, it means that the code retrieved by the controlling program of the testing machine is correct; otherwise, the code retrieved by the controlling program is incorrect.

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